



FORM HDP-1449 (Based on Form PTO-1449)	
PATENT AND TRADEMARK OFFICE	
INFORMATION DISCLOSURE CITATION	
(Use several sheets if necessary)	
Sheet 1 of 1	

ATTORNEY DOCKET NO.	SERIAL NO.
5077-000055	09/881,235
APPLICANT	
Akira Enokihara et al.	
FILING DATE	GROUP
June 14, 2001	2817

U.S. PATENT DOCUMENTS						
Ref. Desig.	Examiner's Initials	Document Number	Date	Name	Class/ Subclass	(If appropriate) Filing Date
1.						

FOREIGN PATENT DOCUMENTS						
Ref. Desig.	Examiner's Initials	Document Number	Date	Country	Class/ Subclass	Translation Yes No
1.	DT	53-076747 A	11/30/1976	Japan		Partial
2.	DT	63-110618	05/16/1988	Japan		Partial
3.	DT	63-010603 A	01/23/1988	Japan		Partial

OTHER DOCUMENTS (including Author, Title, Date, Pertinent Pages, etc.)						
Ref. Desig.	Examiner's Initials					
1.	DT	Notice of Reasons of Rejection for Patent Application No. 2001-176674 mailed September 24, 2003 and English translation.				

Dean Okasha

2/4/04

Examiner:

Date Considered:

EXAMINER: Please initial if citation considered, whether or not citation is in conformance with MPEP 609. Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.

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FOREIGN PATENT DOCUMENTS

Ref. Desig.	Examiner's Initials	Document Number	Date	Country	Class/ Subclass	Translation Yes	No
1.	DT	08065006 A	03/08/1996	Japan		X	Abstract
2.	DT	2000114809 A	04/21/2000	Japan		X	Abstract

OTHER DOCUMENTS (including Author, Title, Date, Pertinent Pages, etc.)

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Examiner: *Ken Tokuda*

Date Considered: 7/16/02

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U.S. PATENT DOCUMENTS

Ref. Desig.	Examiner's Initials	Document Number	Date	Name	Class/ Subclass	(If appropriate) Filing Date
1.	DT	4,028,652	06/07/1977	Wakino et al.	333/209	
2.	DT	4,725,798	02/16/1988	Igarashi	333/212	

FOREIGN PATENT DOCUMENTS

Ref. Desig.	Examiner's Initials	Document Number	Date	Country	Class/ Subclass	Translation Yes	No
1.	DT	63-284902	11/22/1988	Japan	H01P 7/10	Abstract	
2.	DT	63-250201	10/18/1988	Japan	H01P 7/10	Abstract	
3.	DT	EP 0 859 423 A1	08/19/1998	Europe	H01P 1/208		

OTHER DOCUMENTS (including Author, Title, Date, Pertinent Pages, etc.)

Ref. Desig.	Examiner's Initials	
1.	DT	Farhat Abbas et al., "Ultra-high-Q resonators for low-noise, microwave signal generation using sapphire buffer layers and superconducting thin films", Superconductor Science And Technology, Vol. 7, No. 7, July 1, 1994, pp. 495-501.

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